



## FAULT TOLERANCE FOR EMERGING TECHNOLOGIES, EMPHASIZED IN 3D ICS AND CNFET CIRCUITS

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**ABSTRACT:** Emerging technologies such as 3D IC and Carbon Nanotube Transistors (CNFETs), are explored as promising alternatives to continue functional miniaturization at the CMOS endpoint. However, these emerging technologies still face critical challenges for volume production due to the high degree of defect ratio and process variation. In this talk, the speaker will present a number of challenges in fabricating 3D ICs and CNFETs, and describe some recent works and progresses being advocated for these challenges.

**BIOGRAPHY:** Li Jiang received the B.S. degree in computer science & technology from Shanghai Jiao Tong University, Shanghai, China, in 2007, and Ph.D. degree in the Department of Computer Science and Engineering at The Chinese University of Hong Kong, Hong Kong, in 2013.

Since 2014, he has been an Assistant Professor with the Department of Computer Science and Engineering, at Shanghai Jiao Tong University, Shanghai, China. He received the best doctoral thesis award in Asian Test Symposium 2014. His research interests range from computer architecture, computer aided design, VLSI testing and fault tolerance, emphasized in emerging technologies and applications.